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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,966	NAKAZAWA ET AL.	
Examiner	Art Unit	
Lois Zhena	1742	

	SEAR	CHED	
Class	Subclass	Date	Examiner
204	263	9/27/2006	LLZ
204	271	9/27/2006	LLZ
204	276	9/27/2006	LLZ
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEAR		)
	DATE	EXMR
Inventorship Search	9/28/2006	LLZ
Updated EAST Search	9/27/2006	LLZ
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